
HN58C256 Series

32768-word \times 8-bit Electrically Erasable and Programmable
CMOS ROM

HITACHI

ADE-203-092G (Z)

Rev. 7.0

Nov. 29, 1994

Description

The Hitachi HN58C256 is a electrically erasable and programmable ROM organized as 32768-word \times 8-bit. It realizes high speed, low power consumption, and a high level of reliability, employing advanced MNOS memory technology and CMOS process and circuitry technology. It also has a 64-byte page programming function to make its erase and write operations faster.

Features

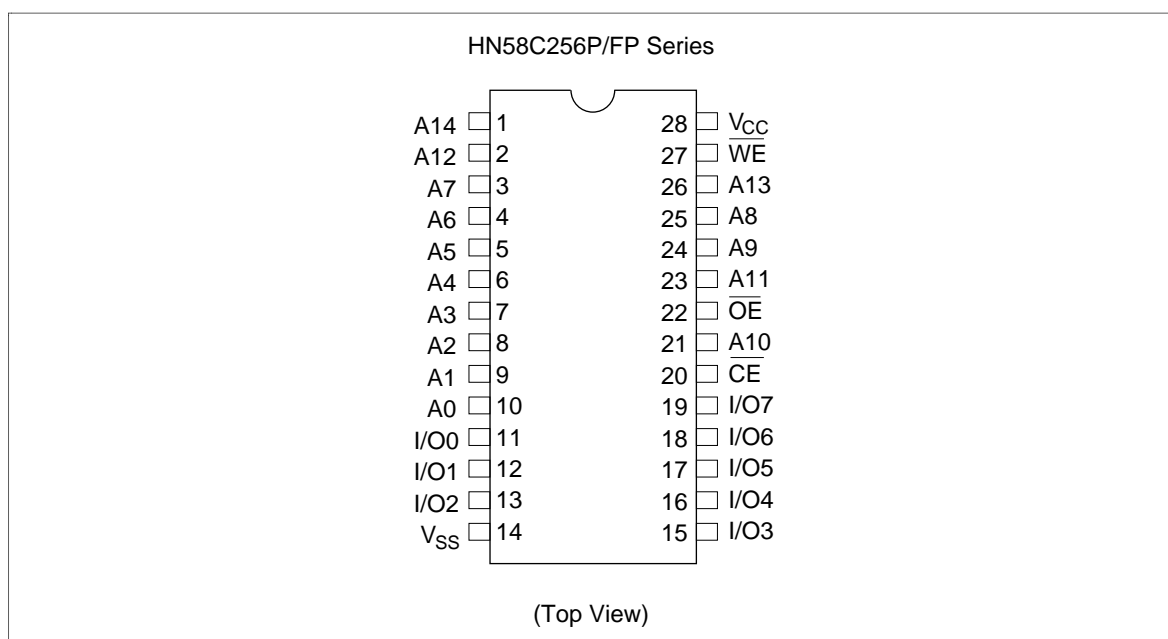
- Single 5 V supply
- On-chip latches: address, data, $\overline{\text{CE}}$, $\overline{\text{OE}}$, $\overline{\text{WE}}$
- Automatic byte write: 10 ms max
- Automatic page write (64 bytes): 10 ms max
- Fast access time: 200 ns max
- Low power dissipation: 20 mW/MHz typ (active)
1.1 mW max (standby)
- $\overline{\text{Data}}$ polling
- Data protection circuit on power on/off
- Conforms to JEDEC byte-wide standard
- Reliable CMOS with MNOS cell technology
- 10^5 erase/write cycles (in page mode)
- 10 year data retention

Ordering Information

Type No.	Access Time	Package
HN58C256P-20	200 ns	600 mil 28-pin plastic DIP (DP-28)
HN58C256FP-20	200 ns	28-pin plastic SOP (Note) (FP-28D)

HN58C256 Series

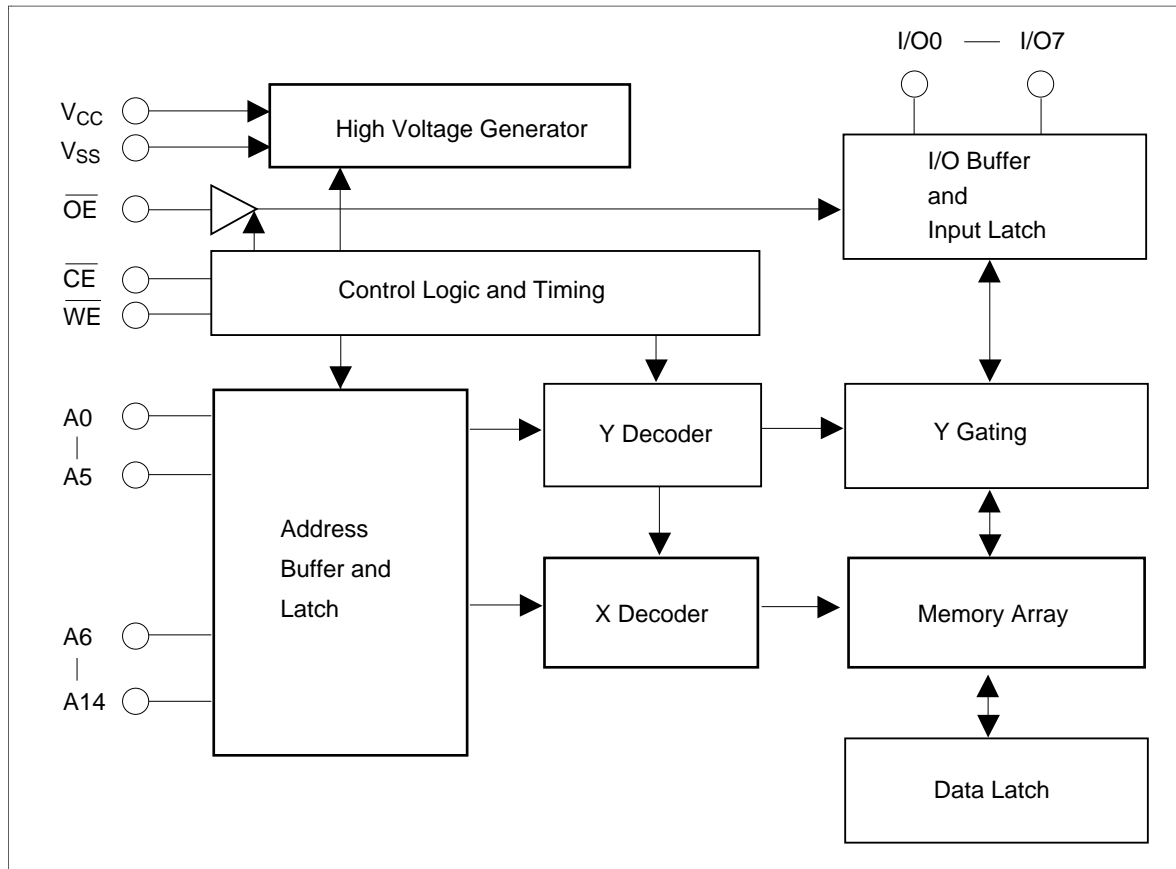
Pin Arrangement



Pin Description

Pin Name	Function
A0 – A14	Address
I/O0 – I/O7	Input/output
OE	Output enable
CE	Chip enable
WE	Write enable
V _{CC}	Power (+5 V)
V _{SS}	Ground

Block Diagram



Mode Selection

Pin Mode	\overline{CE} (20)	\overline{OE} (22)	\overline{WE} (27)	I/O (11 – 13, 15 – 19)
Read	V_{IL}	V_{IL}	V_{IH}	Dout
Standby	V_{IH}	X	X	High-Z
Write	V_{IL}	V_{IH}	V_{IL}	Din
Deselect	V_{IL}	V_{IH}	V_{IH}	High-Z
Write inhibit	X	X	V_{IH}	—
	X	V_{IL}	X	—
Data polling	V_{IL}	V_{IL}	V_{IH}	Data out (I/O7)

Note: X = Don't care

HN58C256 Series

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Supply voltage ^{*1}	V _{CC}	−0.6 to +7.0	V
Input voltage ^{*1}	V _{in}	−0.5 ^{*2} to +7.0	V
Operating temperature range ^{*3}	T _{opr}	0 to +70	°C
Storage temperature range	T _{stg}	−55 to +125	°C

Notes: 1. With respect to V_{SS}
 2. V_{in} min = −3.0 V for pulse width ≤ 50 ns
 3. Including electrical characteristics and data retention.

Recommended DC Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V _{CC}	4.5	5.0	5.5	V
Input voltage	V _{IL}	−0.3	—	0.8	V
	V _{IH}	2.2	—	V _{CC} + 1	V
Operating temperature	T _{opr}	0	—	70	°C

DC Characteristics (T_a = 0 to +70°C, V_{CC} = 5 V ±10%)

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
Input leakage current	I _{LI}	—	—	2	μA	V _{CC} = 5.5 V, V _{in} = 5.5 V
Output leakage current	I _{LO}	—	—	2	μA	V _{CC} = 5.5 V, V _{out} = 5.5/0.4 V
V _{CC} current (standby)	I _{CC1}	—	—	200	μA	$\overline{CE} = V_{CC}$
	I _{CC2}	—	—	1	mA	$\overline{CE} = V_{IH}$
V _{CC} current (active)	I _{CC3}	—	—	12	mA	I _{out} = 0 mA, Duty = 100%, Cycle = 1 μs at V _{CC} = 5.5 V
		—	—	30	mA	I _{out} = 0 mA, Duty = 100%, Cycle = 200 ns at V _{CC} = 5.5 V
Input low voltage	V _{IL}	−0.3 ^{*1}	—	0.8	V	
Input high voltage	V _{IH}	2.2	—	V _{CC} + 1	V	
Output low voltage	V _{OL}	—	—	0.4	V	I _{OL} = 2.1 mA
Output high voltage	V _{OH}	2.4	—	—	V	I _{OH} = −400 μA

Note: 1. V_{IL} min = −1.0 V for pulse width ≤ 50 ns

HN58C256 Series

Capacitance (Ta = 25°C, f = 1 MHz)

Parameter	Symbol	Min	Typ	Max	Unit	Test Conditions
Input capacitance**1	Cin	—	—	6	pF	Vin = 0 V
Output capacitance**1	Cout	—	—	12	pF	Vout = 0 V

Note: 1. This parameter is periodically sampled and not 100 % tested.

AC Characteristics (Ta = 0 to +70°C, V_{CC} = 5 V ± 10 %)

Test Conditions

- Input pulse levels : 0.4 V to 2.4 V
- Input rise and fall time : ≤ 20 ns
- Output load : 1TTL Gate +100 pF
- Reference levels for measuring timing Inputs :
Outputs: 0.8 V and 2.0 V

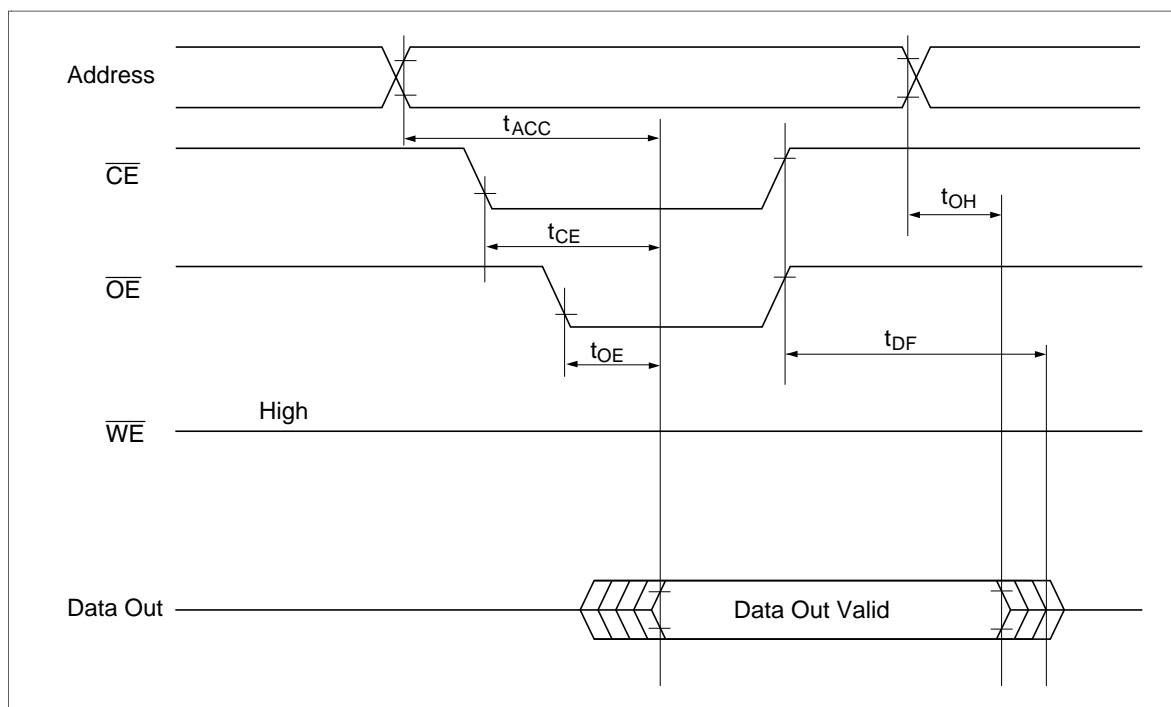
Read Cycle

Parameter	Symbol	Min	Max	Unit	Test Conditions
Address to output delay	t _{ACC}	—	200	ns	$\overline{CE} = \overline{OE} = V_{IL}, \overline{WE} = V_{IH}$
\overline{CE} to output delay	t _{CE}	—	200	ns	$\overline{OE} = V_{IL}, \overline{WE} = V_{IH}$
\overline{OE} to output delay	t _{OE}	10	90	ns	$\overline{CE} = V_{IL}, \overline{WE} = V_{IH}$
Address to output hold	t _{OH}	0	—	ns	$\overline{CE} = \overline{OE} = V_{IL}, \overline{WE} = V_{IH}$
$\overline{OE}, \overline{CE}$ high to output float**1	t _{DF}	0	70	ns	$\overline{CE} = V_{IL}, \overline{WE} = V_{IH}$

Note: 1. t_{DF} is defined at which the outputs achieve the open circuit condition and are no longer driven.

HN58C256 Series

Read Timing Waveform



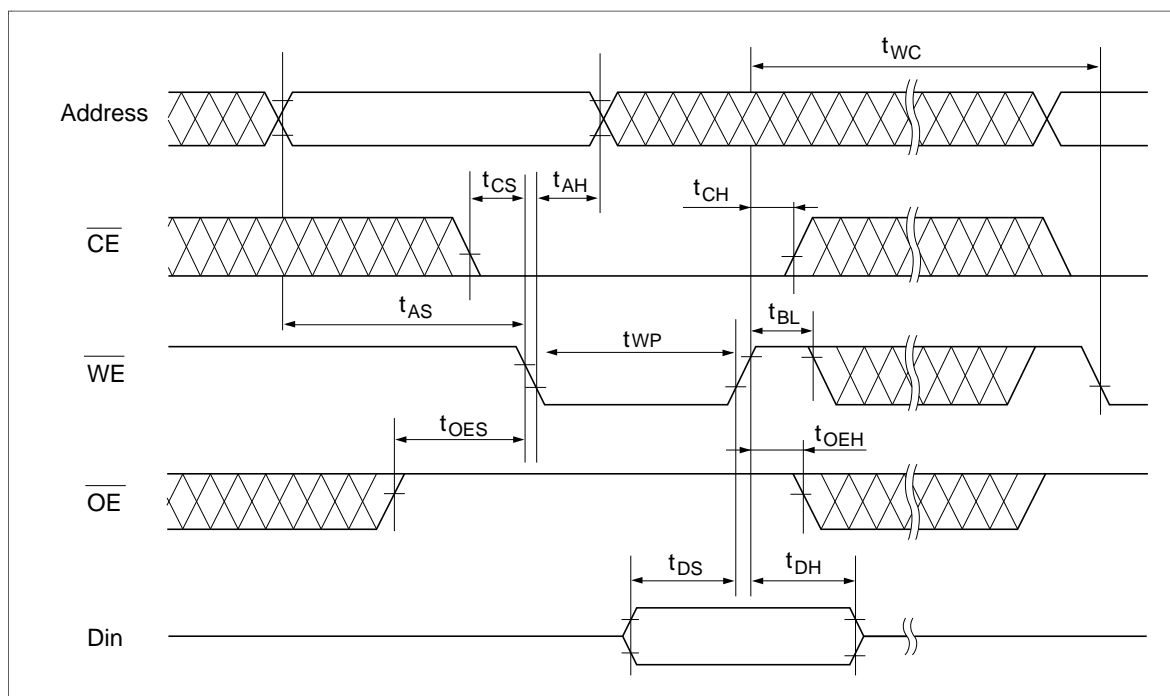
Write Cycle

Parameter	Symbol	Min ^{*1}	Typ	Max	Unit	Test Conditions
Address setup time	t_{AS}	0	—	—	ns	
Address hold time	t_{AH}	150	—	—	ns	
\overline{CE} to write setup time (\overline{WE} controlled)	t_{CS}	0	—	—	ns	
\overline{CE} hold time (\overline{WE} controlled)	t_{CH}	0	—	—	ns	
\overline{WE} to write setup time (\overline{CE} controlled)	t_{WS}	0	—	—	ns	
\overline{WE} hold time (\overline{CE} controlled)	t_{WH}	0	—	—	ns	
\overline{OE} to write setup time	t_{OES}	0	—	—	ns	
\overline{OE} hold time	t_{OEH}	0	—	—	ns	
Data setup time	t_{DS}	100	—	—	ns	
Data hold time	t_{DH}	0	—	—	ns	
\overline{WE} pulse width (\overline{WE} controlled)	t_{WP}	150	—	—	ns	
\overline{CE} pulse width (\overline{CE} controlled)	t_{CW}	150	—	—	ns	
Data latch time	t_{DL}	200	—	—	ns	
Byte lode cycle	t_{BLC}	0.35	—	30	μs	
Byte lode window	t_{BL}	100	—	—	μs	
Write cycle time	t_{WC}	—	—	10^{+2}	ms	
Write start time	t_{DW}	150	—	—	ns	

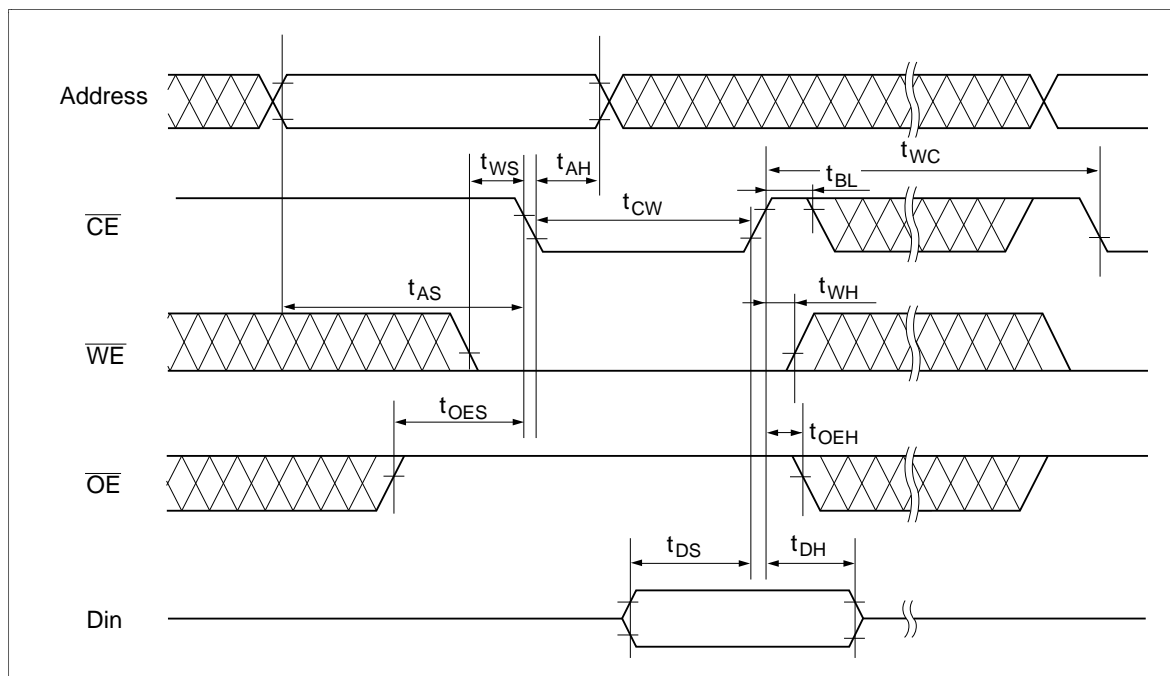
Notes: 1. Use this device in longer cycle than this value.
2. t_{WC} must be longer than this value unless polling technique is used. This device automatically completes the internal write operation within this value.

HN58C256 Series

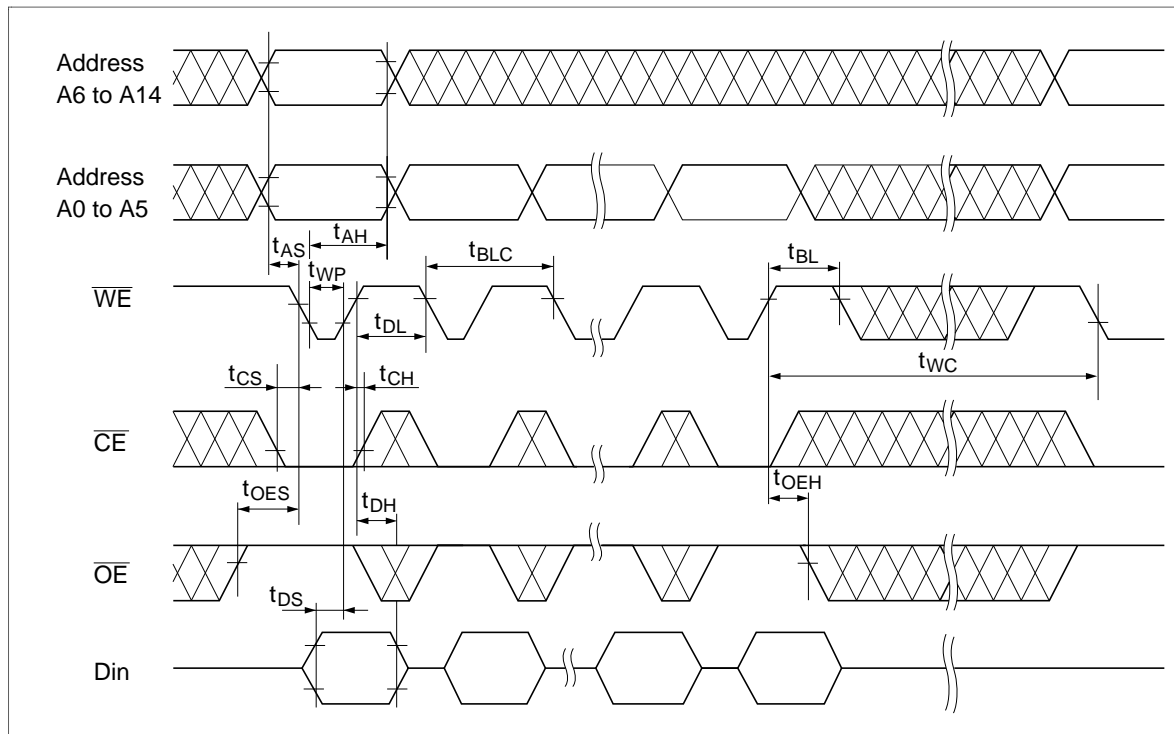
Byte Write Timing Waveform ($\overline{\text{WE}}$ Controlled)



Byte Write Timing Waveform ($\overline{\text{CE}}$ Controlled)

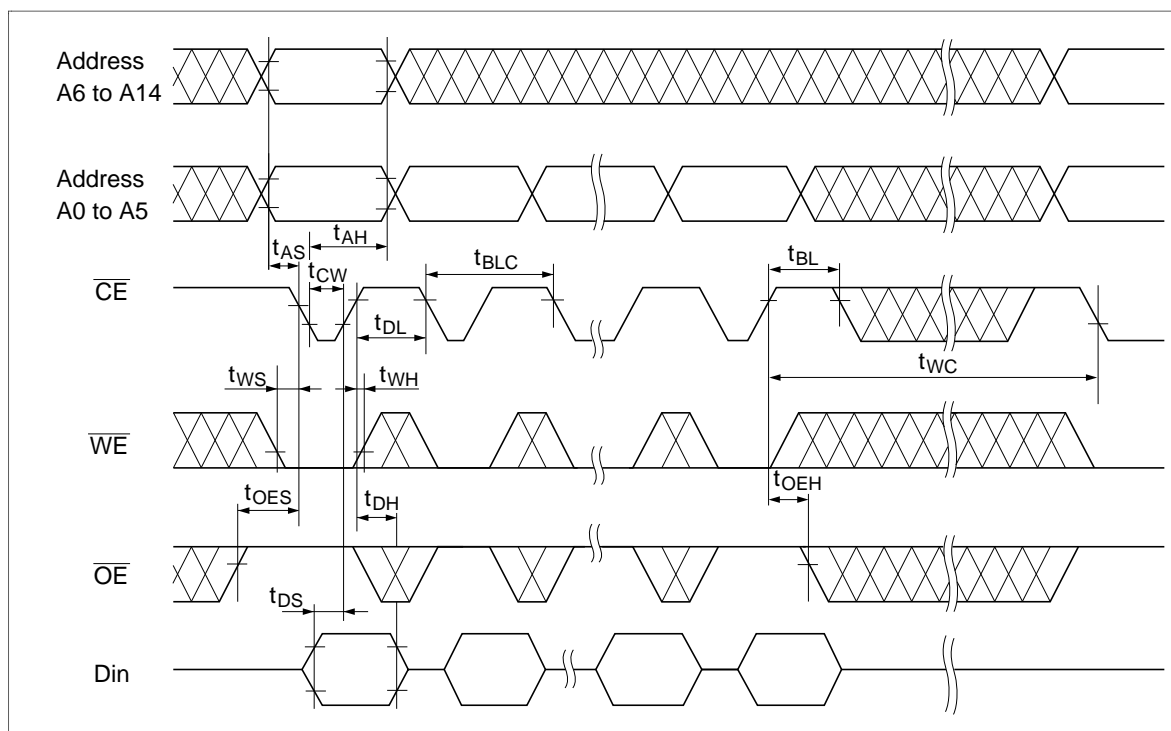


Page Write Timing Waveform (1) ($\overline{\text{WE}}$ Controlled)



HN58C256 Series

Page Write Timing Waveform (2) ($\overline{\text{CE}}$ Controlled)



HN58C256 Series

programmed less than 10^4 cycles.

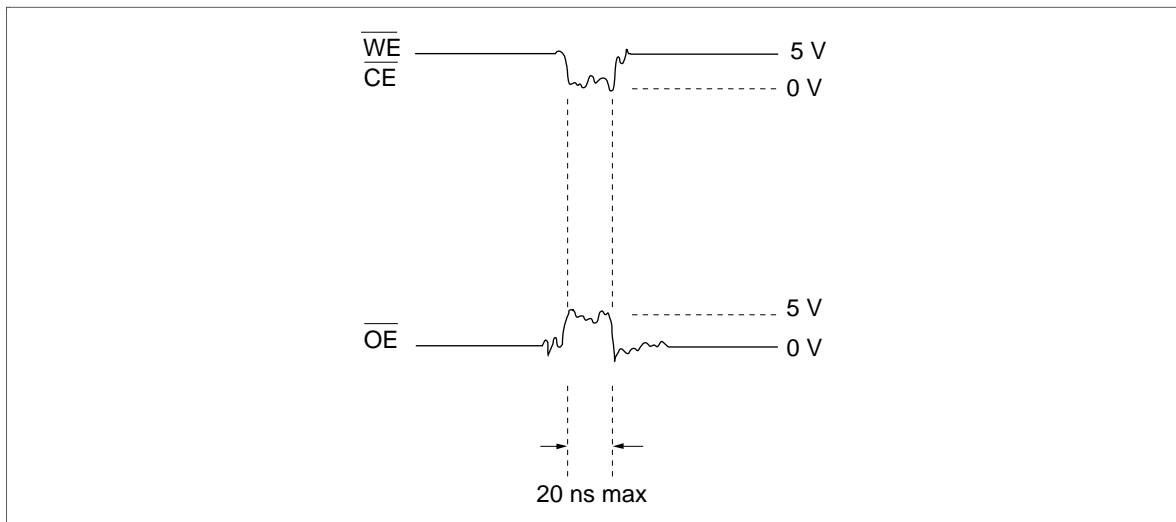
Data Protection

1. Data Protection against Noise on Control Pins ($\overline{\text{CE}}$, $\overline{\text{OE}}$, $\overline{\text{WE}}$) during Operation

During readout or standby, noise on the control pins may act as a trigger and turn the EEPROM to program mode by mistake.

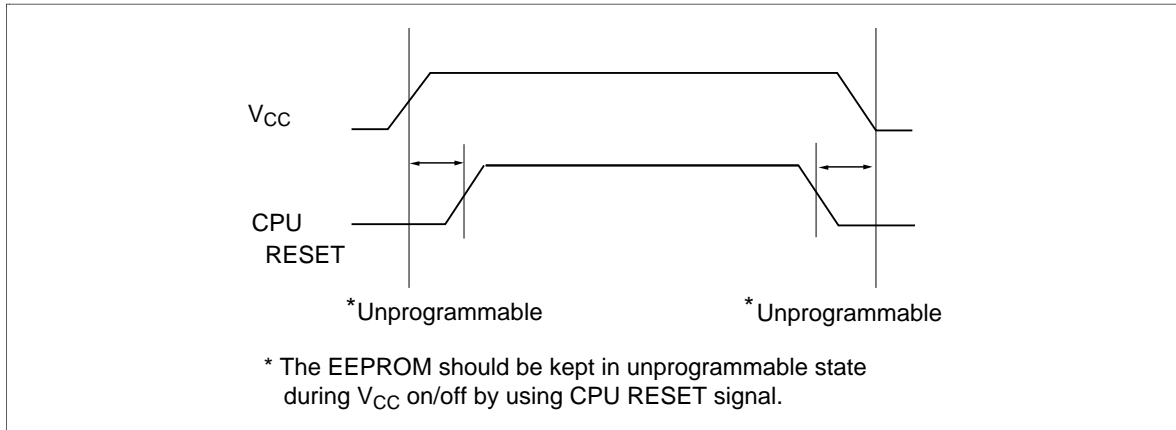
To prevent this phenomenon, this device has a noise cancelation function that cuts noise if its width is 20 ns or less in program mode.

Be careful not to allow noise of a width of more than 20 ns on the control pins.



2. Data Protection at V_{CC} On/Off

When V_{CC} is turned on or off, noise on the control pins generated by external circuits (CPU, etc) may act as a trigger and turn the EEPROM to program mode by mistake. To prevent this unintentional programming, the EEPROM must be kept in an unprogrammable state while the CPU is in an unstable state.



In addition, when V_{CC} is turned on or off, the input level of control pins must be held as shown in the table below.

\overline{CE}	V_{CC}	X	X
\overline{OE}	X	V_{SS}	X
\overline{WE}	X	X	V_{CC}

X: Don't care.

V_{CC} : Pull-up to V_{CC} level.

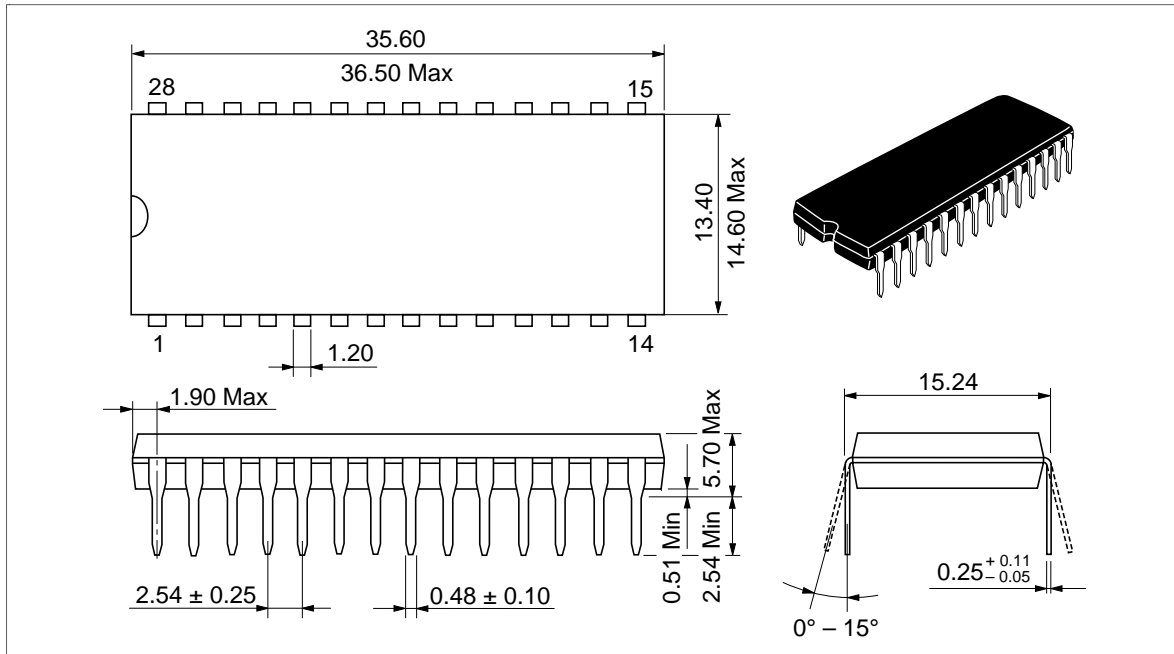
V_{SS} : Pull-down to V_{SS} level.

HN58C256 Series

Package Dimensions

HN58C256P Series (DP-28)

Unit: mm



HN58C256FP Series (FP-28D)

Unit: mm

